



Form PTO-1449 <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (Use several sheets if necessary)	Docket Number 509982000100	Application Number 09/770,997
	Applicant Xinhui NIU and Nickhil JAKATDAR	
	Filing Date January 25, 2001	Group Art Unit <del>2621</del> 2877
	Mailing Date April 9, 2002	

## U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
	1.	7/21/92	5,131,752	Yu et al.			
	2.	11/17/92	5,164,790	McNeil et al.			
	3.	3/4/97	5,607,800	Ziger			
	4.	4/14/98	5,739,909	Blayo et al.			
	5.	11/10/98	5,835,225	Thakur			
	6.	2/2/99	5,867,276	McNeil et al.			
	7.	10/5/99	5,963,329	Conrad et al.			

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

## OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
	8.	N. W. Ashcroft et al., "Solid State Physics", Saunders College Philadelphia, 1976, pgs. 133-135.
	9.	R. M. A. Azzam et al., "Ellipsometry and Polarized Light", Elsevier Science B. V., 1987, book.
	10.	Ch. M. Bishop, "Neural Networks for Pattern Recognition", Ch. 4, 1995, pp. 117-161.
	11.	S. Bushman et al., "Scatterometry Measurements for Process Monitoring of Gate Etch", AEC/APC Workshop IX, Sematech, Sept. 20-24, 1997, pp. 148-158.
	12.	G. Granet et al., "Efficient implementation of the coupled-wave method for metallic lamellar in TM polarization", J. Opt. Soc. Am. vol. 13, no. 5, May 1996, pp. 1019-1023.
	13.	O. S. Heavens, "Optical Properties of Thin Solid Films", Dover Publications, Inc. 1955, book.
	14.	P. Lalanne et al., "Highly improved convergence of the coupled-wave method for TM polarization", J. Opt. Soc. Am. vol. 13, no. 4, April 1996, pp. 779-784.
	15.	L. Li et al., "Convergence of the coupled-wave method for metallic lamellar diffraction gratings", J. Opt. Soc. Am. vol. 10, no. 6, June 1993, pp. 1184-1189.

EXAMINER:

DATE CONSIDERED:

27 July 2004

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.



PTO/SB/08 (2-92)  
Sheet 2 of 2

Form PTO-1449 <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (Use several sheets if necessary)	Docket Number 509982000100	Application Number 09/770,997
	Applicant Xinhui NIU and Nickhil JAKATDAR	
	Filing Date January 25, 2001	Group Art Unit <u>2621 2877</u>
	Mailing Date April 9, 2002	

	16.	D. Maystre, "A new general integral theory for dielectric coated gratings", J. of Opt. Soc. of Amer. vol. 68 (4), Apr. 78, pp. 189-194.
	17.	M. G. Moharam et al., "Rigorous coupled-wave analysis of planar-grating diffraction", J. Opt. Soc. Am. vol. 71, no. 7/July 1981, pp. 811-818.
	18.	M. G. Moharam et al., "Formulation for stable and efficient implementation of the rigorous coupled-wave analysis of binary gratings", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1068-1076.
	19.	Moharam et al., "Stable implementation of the rigorous coupled-wave analysis for surface - relief gratings: enhanced transmittance matrix approach", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1077-1086.
	20.	M. Nevriere et al., "Systematic Study of Resonances of Holographic Thin Film Couplers", Optics Com. vol. 9 (1), 1973, pp. 205-209.
	21.	A. R. Neureuther et al., "Numerical Methods for the Analysis of Scattering from Nonplanar Periodic Structures", URSI Symposium on Electromag. Waves, 1969, pp. 185-188.
	22.	W. H. Press et al., "Numerical Recipes in C", Art of Scien. Computing 2nd Ed., 1986, pp. 29-38.
	23.	J. A. Rice, "Mathematical Statistics and Data Analysis" sec. ed., ch. 14, Duxbury Press, 1995, pp. 507-570.

RECEIVED

APR 17 2002

Technology Center 2600

EXAMINER:	DATE CONSIDERED: <u>27 July 2004</u>
EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.	